## Lecture Notes 15 Hypothesis Testing (Chapter 10)

## 1 Introduction

Let  $X_1, \ldots, X_n \sim p_\theta(x)$ . Suppose we we want to know if  $\theta = \theta_0$  or not, where  $\theta_0$  is a specific value of  $\theta$ . For example, if we are flipping a coin, we may want to know if the coin is fair; this corresponds to  $p = 1/2$ . If we are testing the effect of two drugs — whose means effects are  $\theta_1$  and  $\theta_2$  — we may be interested to know if there is no difference, which corresponds to  $\theta_1 - \theta_2 = 0$ .

We formalize this by stating a *null hypothesis*  $H_0$  and an alternative hypothesis  $H_1$ . For example:

$$
H_0: \theta = \theta_0 \quad \text{versus} \quad \theta \neq \theta_0.
$$

More generally, consider a parameter space Θ. We consider

$$
H_0: \theta \in \Theta_0
$$
 versus  $H_1: \theta \in \Theta_1$ 

where  $\Theta_0 \cap \Theta_1 = \emptyset$ . If  $\Theta_0$  consists of a single point, we call this a *simple null hypothesis*. If  $\Theta_0$  consists of more than one point, we call this a *composite null hypothesis*.

Example 1  $X_1, \ldots, X_n \sim \text{Bernoulli}(p)$ .

$$
H_0: p = \frac{1}{2}
$$
  $H_1: p \neq \frac{1}{2}.$   $\Box$ 

The question is not whether  $H_0$  is true or false. The question is whether there is sufficient evidence to reject  $H_0$ , much like a court case. Our possible actions are: reject  $H_0$  or retain (don't reject)  $H_0$ .



Warning: Hypothesis testing should only be used when it is appropriate. Often times, people use hypothesis testing when it would be much more appropriate to use confidence intervals.

**Notation:** Let  $\Phi$  be the cdf of a standard Normal random variable Z. For  $0 < \alpha < 1$ , let

$$
z_{\alpha} = \Phi^{-1}(1 - \alpha).
$$

Hence,

$$
P(Z > z_\alpha) = \alpha.
$$

Also,  $P(Z < -z_\alpha) = \alpha$ . In these notes we sometimes write  $p(x; \theta)$  instead of  $p_\theta(x)$ .

# 2 Constructing Tests

Hypothesis testing involves the following steps:

- 1. Choose a test statistic  $T_n = T_n(X_1, \ldots, X_n)$ .
- 2. Choose a rejection region R.
- 3. If  $T_n \in R$  we reject  $H_0$  otherwise we retain  $H_0$ .

**Example 2** Let  $X_1, \ldots, X_n \sim \text{Bernoulli}(p)$ . Suppose we test

$$
H_0: p = \frac{1}{2} \qquad H_1: p \neq \frac{1}{2}.
$$

Let  $T_n = n^{-1} \sum_{i=1}^n X_i$  and  $R = \{x_1, \ldots, x_n : |T_n(x_1, \ldots, x_n) - 1/2| > \delta\}$ . So we reject  $H_0$  if  $|T_n - 1/2| > \delta.$ 

We need to choose  $T$  and  $R$  so that the test has good statistical properties. We will consider the following tests:

- 1. The Neyman-Pearson Test
- 2. The Wald test
- 3. The Likelihood Ratio Test (LRT)
- 4. The permutation test.

Before we discuss these methods, we first need to talk about how we evaluate tests.

## 3 Error Rates and Power

Suppose we reject  $H_0$  when  $(X_1, \ldots, X_n) \in R$ . Define the *power function* by

$$
\beta(\theta) = P_{\theta}(X_1, \ldots, X_n \in R).
$$

We want  $\beta(\theta)$  to be small when  $\theta \in \Theta_0$  and we want  $\beta(\theta)$  to be large when  $\theta \in \Theta_1$ . The general strategy is:

1. Fix  $\alpha \in [0,1]$ .

2. Now try to maximize  $\beta(\theta)$  for  $\theta \in \Theta_1$  subject to  $\beta(\theta) \leq \alpha$  for  $\theta \in \Theta_0$ .

We need the following definitions. A test is size  $\alpha$  if

$$
\sup_{\theta \in \Theta_0} \beta(\theta) \le \alpha.
$$

**Example 3**  $X_1, \ldots, X_n \sim N(\theta, \sigma^2)$  with  $\sigma^2$  known. Suppose we test

$$
H_0: \theta = \theta_0, \qquad H_1: \theta > \theta_0.
$$

This is called a **one-sided alternative**. Suppose we reject  $H_0$  if  $T_n > c$  where

$$
T_n = \frac{\overline{X}_n - \theta_0}{\sigma / \sqrt{n}}.
$$

Then

$$
\beta(\theta) = P_{\theta} \left( \frac{\overline{X}_n - \theta_0}{\sigma/\sqrt{n}} > c \right) = P_{\theta} \left( \frac{\overline{X}_n - \theta}{\sigma/\sqrt{n}} > c + \frac{\theta_0 - \theta}{\sigma/\sqrt{n}} \right)
$$

$$
= P \left( Z > c + \frac{\theta_0 - \theta}{\sigma/\sqrt{n}} \right) 1 - \Phi \left( c + \frac{\theta_0 - \theta}{\sigma/\sqrt{n}} \right)
$$

where  $\Phi$  is the cdf of a standard Normal and  $Z \sim \Phi$ . Now

$$
\sup_{\theta \in \Theta_0} \beta(\theta) = \beta(\theta_0) = 1 - \Phi(c).
$$

To get a size  $\alpha$  test, set  $1 - \Phi(c) = \alpha$  so that

$$
c=z_\alpha
$$

where  $z_{\alpha} = \Phi^{-1}(1-\alpha)$ . Our test is: reject  $H_0$  when

$$
T_n = \frac{\overline{X}_n - \theta_0}{\sigma/\sqrt{n}} > z_\alpha.
$$

**Example 4**  $X_1, \ldots, X_n \sim N(\theta, \sigma^2)$  with  $\sigma^2$  known. Suppose

$$
H_0: \theta = \theta_0, \qquad H_1: \theta \neq \theta_0.
$$

This is called a **two-sided** alternative. We will reject  $H_0$  if  $|T_n| > c$  where  $T_n$  is defined as before. Now

$$
\beta(\theta) = P_{\theta}(T_n < -c) + P_{\theta}(T_n > c)
$$
  
\n
$$
= P_{\theta}\left(\frac{\overline{X}_n - \theta_0}{\sigma/\sqrt{n}} < -c\right) + P_{\theta}\left(\frac{\overline{X}_n - \theta_0}{\sigma/\sqrt{n}} > c\right)
$$
  
\n
$$
= P\left(Z < -c + \frac{\theta_0 - \theta}{\sigma/\sqrt{n}}\right) + P\left(Z > c + \frac{\theta_0 - \theta}{\sigma/\sqrt{n}}\right)
$$
  
\n
$$
= \Phi\left(-c + \frac{\theta_0 - \theta}{\sigma/\sqrt{n}}\right) + 1 - \Phi\left(c + \frac{\theta_0 - \theta}{\sigma/\sqrt{n}}\right)
$$
  
\n
$$
= \Phi\left(-c + \frac{\theta_0 - \theta}{\sigma/\sqrt{n}}\right) + \Phi\left(-c - \frac{\theta_0 - \theta}{\sigma/\sqrt{n}}\right)
$$

since  $\Phi(-x) = 1 - \Phi(x)$ . The size is

$$
\beta(\theta_0) = 2\Phi(-c).
$$

To get a size  $\alpha$  test we set  $2\Phi(-c) = \alpha$  so that  $c = -\Phi^{-1}(\alpha/2) = \Phi^{-1}(1 - \alpha/2) = z_{\alpha/2}$ . The test is: reject  $H_0$  when

$$
|T| = \left| \frac{\overline{X}_n - \theta_0}{\sigma / \sqrt{n}} \right| > z_{\alpha/2}.
$$

#### 4 The Neyman-Pearson Test

(Not in the book.) Let  $\mathcal{C}_{\alpha}$  denote all level  $\alpha$  tests. A test in  $\mathcal{C}_{\alpha}$  with power function  $\beta$  is uniformly most powerful (UMP) if the following holds: if  $\beta'$  is the power function of any other test in  $\mathcal{C}_{\alpha}$  then  $\beta(\theta) \leq \beta'(\theta)$  for all  $\theta \in \Theta_1$ .

Consider testing  $H_0: \theta = \theta_0$  versus  $H_1: \theta = \theta_1$ . (Simple null and simple alternative.)

**Theorem 5** Let  $L(\theta) = p(X_1, \ldots, X_n; \theta)$  and

$$
T_n = \frac{L(\theta_1)}{L(\theta_0)}.
$$

Suppose we reject  $H_0$  if  $T_n > k$  where k is chosen so that

$$
P_{\theta_0}(X^n \in R) = \alpha.
$$

This test is a UMP level  $\alpha$  test.

The Neyman-Pearson test is quite limited because it can be used only for testing a simple null versus a simple alternative. So it does not get used in practice very often. But it is important from a conceptual point of view.

# 5 The Wald Test

Let

$$
T_n = \frac{\hat{\theta}_n - \theta_0}{\text{se}}
$$

where  $\hat{\theta}$  is an asymptotically Normal estimator and se is the estimated standard error of  $\hat{\theta}$ (or the standard error under  $H_0$ ). Under  $H_0$ ,  $T_n \rightsquigarrow N(0, 1)$ . Hence, an asymptotic level  $\alpha$ test is to reject when  $|T_n| > z_{\alpha/2}$ . That is

$$
P_{\theta_0}(|T_n| > z_\alpha) \to \alpha.
$$

For example, with Bernoulli data, to test  $H_0: p = p_0$ ,

$$
T_n = \frac{\widehat{p} - p_0}{\sqrt{\frac{\widehat{p}(1-\widehat{p})}{n}}}.
$$

You can also use

$$
T_n = \frac{\widehat{p} - p_0}{\sqrt{\frac{p_0(1 - p_0)}{n}}}.
$$

In other words, to compute the standard error, you can replace  $\theta$  with an estimate  $\widehat{\theta}$  or by the null value  $\theta_0$ .

# 6 The Likelihood Ratio Test (LRT)

This test is simple: reject  $H_0$  if  $\lambda(x_1, \ldots, x_n) \leq c$  where

$$
\lambda(x_1,\ldots,x_n)=\frac{\sup_{\theta\in\Theta_0}L(\theta)}{\sup_{\theta\in\Theta}L(\theta)}=\frac{L(\theta_0)}{L(\widehat{\theta})}
$$

where  $\widehat{\theta}_0$  maximizes  $L(\theta)$  subject to  $\theta \in \Theta_0$ .

Example 6  $X_1, \ldots, X_n \sim N(\theta, 1)$ . Suppose

$$
H_0: \theta = \theta_0, \qquad H_1: \theta \neq \theta_0.
$$

After some algebra,

$$
\lambda = \exp\left\{-\frac{n}{2}(\overline{X}_n - \theta_0)^2\right\}.
$$

So

$$
R = \{x : \lambda \le c\} = \{x : |\overline{X} - \theta_0| \ge c'\}
$$

where  $c' = \sqrt{-2 \log c/n}$ . Choosing c' to make this level  $\alpha$  gives: reject if  $|T_n| > z_{\alpha/2}$  where  $T_n =$ √  $\overline{n}(X - \theta_0)$  which is the test we constructed before.

Example 7  $X_1, \ldots, X_n \sim N(\theta, \sigma^2)$ . Suppose

$$
H_0: \theta = \theta_0, \qquad H_1: \theta \neq \theta_0.
$$

Then

$$
\lambda(x_1,\ldots,x_n) = \frac{L(\theta_0,\widehat{\sigma}_0)}{L(\widehat{\theta},\widehat{\sigma})}
$$

where  $\hat{\sigma}_0$  maximizes the likelihood subject to  $\theta = \theta_0$ .

**Exercise:** Show that  $\lambda(x_1, \ldots, x_n) < c$  corresponds to rejecting when  $|T_n| > k$  for some constant k where

$$
T_n = \frac{X_n - \theta_0}{S / \sqrt{n}}.
$$

Under  $H_0$ ,  $T_n$  has a t-distribution with  $n-1$  degrees of freedom. So the final test is: reject  $H_0$  if

$$
|T_n| > t_{n-1,\alpha/2}.
$$

This is called Student's t-test. It was invented by William Gosset working at Guiness Breweries and writing under the pseudonym Student.

We can simplify the LRT by using an asymptotic approximation. First, some notation:

**Notation:** Let  $W \sim \chi_p^2$ . Define  $\chi_{p,\alpha}^2$  by  $P(W > \chi^2_{p,\alpha}) = \alpha.$ 

**Theorem 8** Consider testing  $H_0: \theta = \theta_0$  versus  $H_1: \theta \neq \theta_0$  where  $\theta \in \mathbb{R}$ . Under  $H_0$ ,

$$
-2\log\lambda(X_1,\ldots,X_n)\leadsto\chi_1^2.
$$

Hence, if we let  $T_n = -2 \log \lambda(X^n)$  then

$$
P_{\theta_0}(T_n > \chi^2_{1,\alpha}) \to \alpha
$$

as  $n \to \infty$ .

Proof. Using a Taylor expansion:

$$
\ell(\theta) \approx \ell(\widehat{\theta}) + \ell'(\widehat{\theta})(\theta - \widehat{\theta}) + \ell''(\widehat{\theta})\frac{(\theta - \widehat{\theta})^2}{2} = \ell(\widehat{\theta}) + \ell''(\widehat{\theta})\frac{(\theta - \widehat{\theta})^2}{2}
$$

and so

$$
-2\log \lambda(x_1, \dots, x_n) = 2\ell(\widehat{\theta}) - 2\ell(\theta_0)
$$
  
\n
$$
\approx 2\ell(\widehat{\theta}) - 2\ell(\widehat{\theta}) - \ell''(\widehat{\theta})(\theta - \widehat{\theta})^2 = -\ell''(\widehat{\theta})(\theta - \widehat{\theta})^2
$$
  
\n
$$
= \frac{-\ell''(\widehat{\theta})}{I_n(\theta_0)} I_n(\theta_0) (\sqrt{n}(\widehat{\theta} - \theta_0))^2 = A_n \times B_n.
$$

Now  $A_n \xrightarrow{P} 1$  by the WLLN and  $\sqrt{B_n} \rightsquigarrow N(0, 1)$ . The result follows by Slutsky's theorem.  $\blacksquare$ 

Example 9  $X_1, \ldots, X_n \sim \text{Poisson}(\lambda)$ . We want to test  $H_0 : \lambda = \lambda_0$  versus  $H_1 : \lambda \neq \lambda_0$ . Then

$$
-2\log \lambda(x^n) = 2n[(\lambda_0 - \widehat{\lambda}) - \widehat{\lambda}\log(\lambda_0/\widehat{\lambda})].
$$

We reject  $H_0$  when  $-2 \log \lambda(x^n) > \chi^2_{1,\alpha}$ .

Now suppose that  $\theta = (\theta_1, \dots, \theta_k)$ . Suppose that  $H_0 : \theta \in \Theta_0$  fixes some of the parameters. Then, under conditions,

$$
T_n = -2\log \lambda(X_1,\ldots,X_n) \rightsquigarrow \chi^2_{\nu}
$$

where

$$
\nu = \dim(\Theta) - \dim(\Theta_0).
$$

Therefore, an asymptotic level  $\alpha$  test is: reject  $H_0$  when  $T_n > \chi^2_{\nu,\alpha}$ .

**Example 10** Consider a multinomial with  $\theta = (p_1, \ldots, p_5)$ . So

$$
L(\theta) = p_1^{y_1} \cdots p_5^{y_5}.
$$

Suppose we want to test

 $H_0: p_1 = p_2 = p_3$  and  $p_4 = p_5$ 

versus the alternative that  $H_0$  is false. In this case

$$
\nu = 4 - 1 = 3.
$$

The LRT test statistic is

$$
\lambda(x_1, \ldots, x_n) = \frac{\prod_{i=1}^5 \widehat{p}_{0j}^{Y_j}}{\prod_{i=1}^5 \widehat{p}_j^{Y_j}}
$$

where  $\hat{p}_j = Y_j/n$ ,  $\hat{p}_{10} = \hat{p}_{20} = \hat{p}_{30} = (Y_1 + Y_2 + Y_3)/n$ ,  $\hat{p}_{40} = \hat{p}_{50} = (1 - 3\hat{p}_{10})/2$ .<br>These solentians are an  $n/91$ , Make sure we wedenteed them. Now we major H, it These calculations are on p 491. Make sure you understand them. Now we reject  $H_0$  if  $-2\lambda(X_1,\ldots,X_n) > \chi^2_{3,\alpha}$ .

## 7 p-values

When we test at a given level  $\alpha$  we will reject or not reject. It is useful to summarize what levels we would reject at and what levels we woud not reject at.

#### The p-value is the smallest  $\alpha$  at which we would reject  $H_0$ .

In other words, we reject at all  $\alpha \geq p$ . So, if the pvalue is 0.03, then we would reject at  $\alpha = 0.05$  but not at  $\alpha = 0.01$ .

Hence, to test at level  $\alpha$  when  $p < \alpha$ .

**Theorem 11** Suppose we have a test of the form: reject when  $T(X_1, \ldots, X_n) > c$ . Then the p-value is

$$
p = \sup_{\theta \in \Theta_0} P_{\theta}(T_n(X_1, \ldots, X_n) \geq T_n(x_1, \ldots, x_n))
$$

where  $x_1, \ldots, x_n$  are the observed data and  $X_1, \ldots, X_n \sim p_{\theta_0}$ .

Example 12  $X_1, \ldots, X_n \sim N(\theta, 1)$ . Test that  $H_0 : \theta = \theta_0$  versus  $H_1 : \theta \neq \theta_0$ . We reject when  $|T_n|$  is large, where  $T_n = \sqrt{n}(X_n - \theta_0)$ . Let  $t_n$  be the obsrved value of  $T_n$ . Let  $Z \sim N(0, 1)$ . Then,

$$
p = P_{\theta_0}(|\sqrt{n}(\overline{X}_n - \theta_0)| > t_n) = P(|Z| > t_n) = 2\Phi(-|t_n|).
$$

Theorem 13 Under  $H_0$ ,  $p \sim \text{Unif}(0, 1)$ .

**Important.** Note that p is NOT equal to  $P(H_0|X_1,\ldots,X_n)$ . The latter is a Bayesian quantity which we will discuss later.

## 8 The Permutation Test

This is a very cool test. It is distribution free and it does not involve any asymptotic approximations.

Suppose we have data

$$
X_1,\ldots,X_n \sim F
$$

and

$$
Y_1,\ldots,Y_m\sim G.
$$

We want to test:

$$
H_0: F = G \quad \text{versus} \quad H_1: F \neq G.
$$

Let

$$
Z=(X_1,\ldots,X_n,Y_1,\ldots,Y_m).
$$

Create labels

$$
L = (\underbrace{1, \ldots, 1}_{n \text{ values}}, \underbrace{2, \ldots, 2}_{m \text{ values}}).
$$

A test statistic can be written as a function of Z and L. For example, if

$$
T = |\overline{X}_n - \overline{Y}_m|
$$

then we can write

$$
T = \left| \frac{\sum_{i=1}^{N} Z_i I(L_i = 1)}{\sum_{i=1}^{N} I(L_i = 1)} - \frac{\sum_{i=1}^{N} Z_i I(L_i = 2)}{\sum_{i=1}^{N} I(L_i = 2)} \right|
$$

where  $N = n + m$ . So we write  $T = g(L, Z)$ .

Define

$$
p = \frac{1}{N!} \sum_{\pi} I(g(L_{\pi}, Z) > g(L, Z))
$$

where  $L_{\pi}$  is a permutation of the labels and the sum is over all permutations. Under  $H_0$ , permuting the labels does not change the distribution. In other words,  $g(L, Z)$  has an equal chance of having any rank among all the permuted values. That is, under  $H_0$ ,  $\approx$  Unif(0, 1) and if we reject when  $p < \alpha$ , then we have a level  $\alpha$  test.

Summing over all permutations is infeasible. But it suffices to use a random sample of permutations. So we do this:

- 1. Compute a random permutation of the labels and compute  $W$ . Do this  $K$  times giving values  $T^{(1)}, \ldots, T^{(K)}$ .
- 2. Compute the p-value

$$
\frac{1}{K} \sum_{j=1}^{K} I(T^{(j)} > T).
$$